

WHAT IS CLAIMED IS:

1. A method for determining if there is a temperature dependent hopping pixel defect in an image sensor, comprising the steps of:
 - (a) providing an image sensor in a heated environment having a temperature selected such that hopping pixel defects can be detected; and
 - (b) operating the image sensor and analyzing the output of the pixels of the image sensor to determine if there are hopping pixel defects.
2. The method of claim 1 wherein step (b) further includes capturing the output signals in a voltage format provided by the pixels a number of times and determining if there are hopping pixel defects in the output signals.
3. The method of claim 2 processing the output signals to produce a visual display which designates the pixels which have hopping pixel defects and the relative amplitude of such defects.
4. The method of claim 2 wherein the image sensor is a linear or area sensor.
5. The method of claim 2 processing the output signals to produce a visual display which designates the pixels which have hopping pixel defects and the relative amplitude of such defects.

2025 RELEASE UNDER E.O. 14176